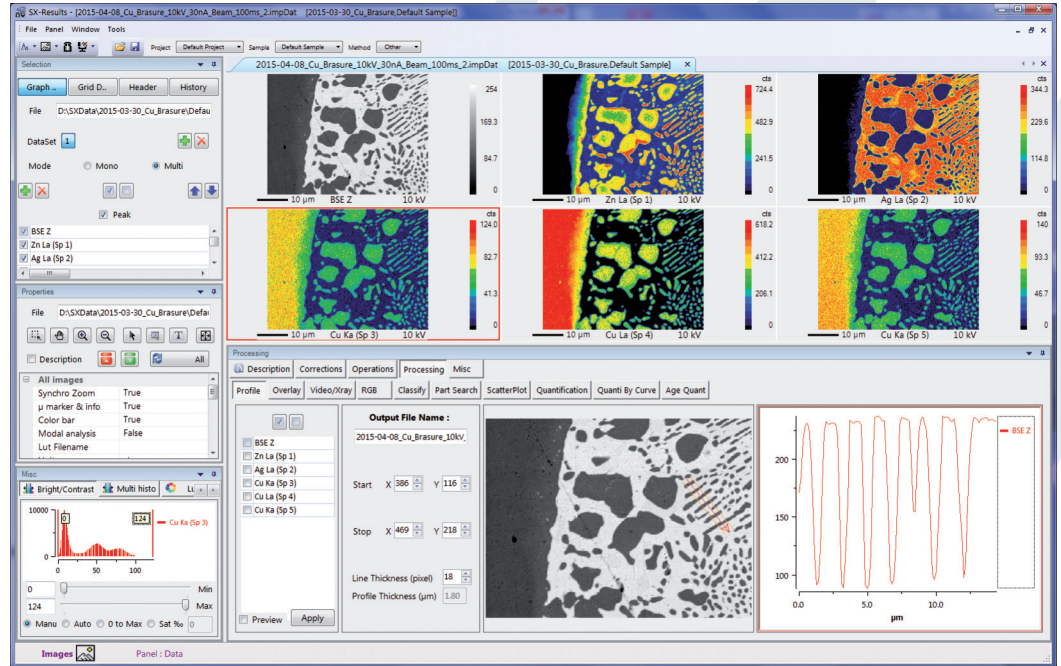


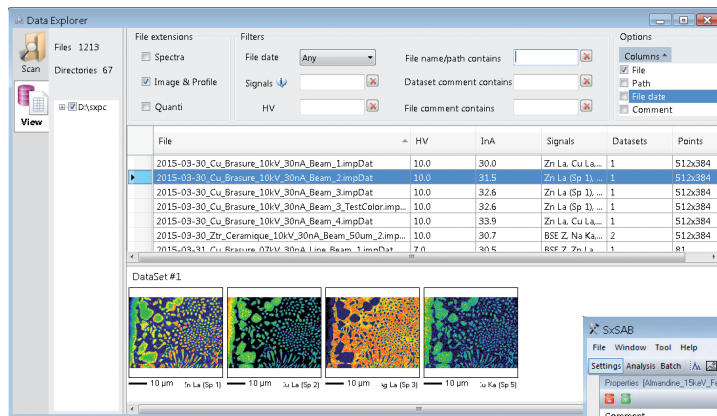
PeakSight 6.0 is the latest version of the Automation & Analysis software for CAMECA SX Electron Probe MicroAnalyzers.

Version 6.0 comes with a completely redesigned interface for **more ease-of-use**. A set of new functionalities ensures enhanced data acquisition and processing, as well as **improved quantification accuracy**.

PeakSight 6.0 is now delivered with all SXFive and SXFiveFE. Upgrades are available for SX 100, SXFive and SXFiveFE. If you are not under service contract, please contact your local CAMECA sales representative for upgrade details.



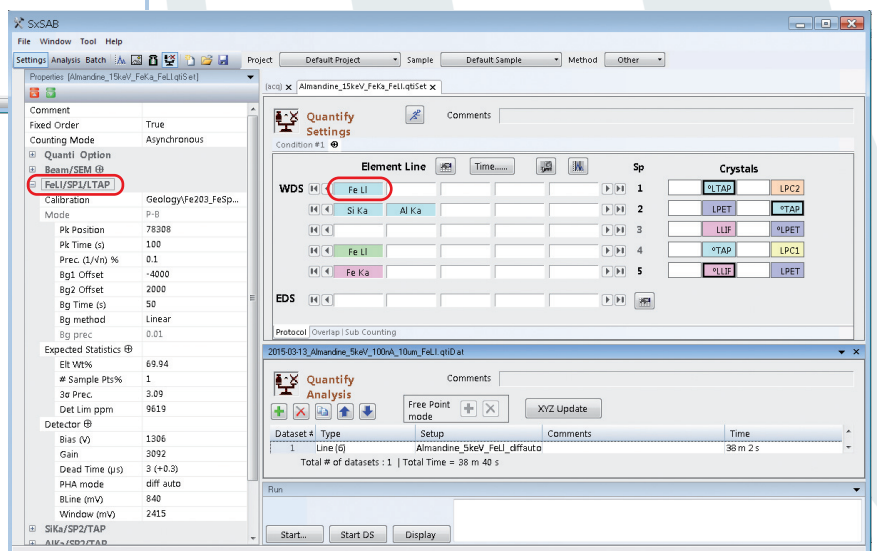
Based on .net environment and compatible with the latest Windows versions, PeakSight 6.0 offers a flexible, multi-document interface allowing **easy control of all steps of your EPMA project**.

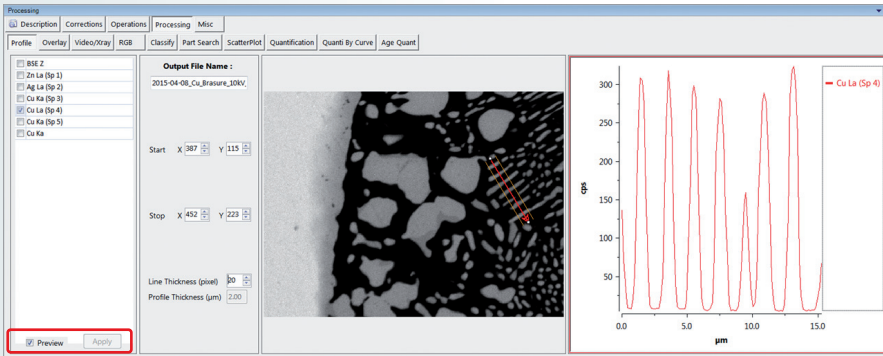


- **New Data Explorer:** Save time and manage your project more easily thanks to this powerful data finder! Calibration data (settings and analysis) are stored in a shared folder, sorted by main application (geology, metallurgy, others).
- **New unified 'SAB' control panel:** Setting, Acquisition and Batch processing tasks are now performed from the same user-friendly control panel, ergonomics are identical whatever the applications (spectra, calibration, quantification, mapping...)

- **L1 lines:** PeakSight 6.0 can acquire and process L1 X-ray lines\*, which provide a more accurate quantification of the first series transition metals than  $L\alpha$  lines. New Mass Absorption Coefficient tables are available (Henke, Heinrich, Chantler...), also contributing to an **improved quantification accuracy**.

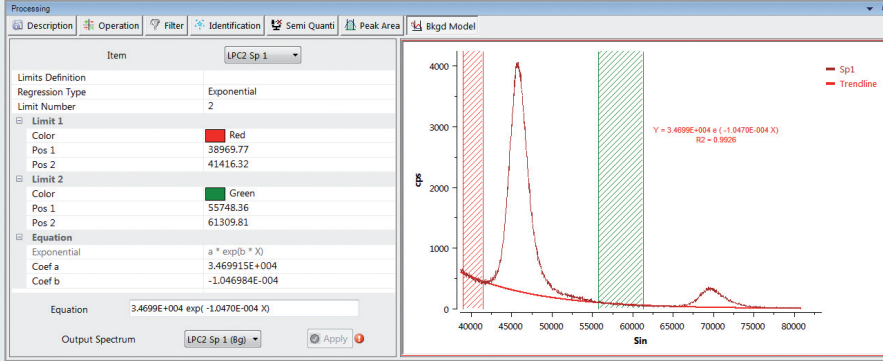
\*For more information, you may refer to 'Accurate EPMA quantification of the First Series Transition Metals using L1 lines', poster pres. at EMAS 2015.





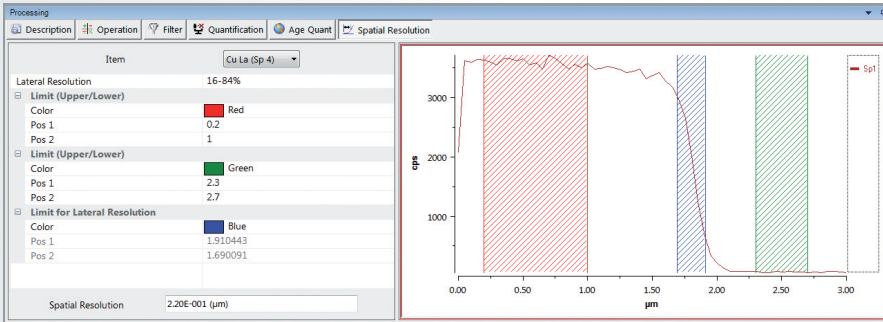
• **New Preview function:**  
View the results of your data-processing first, data will only be modified after clicking on *Apply* to validate the process.

• **History panel:**  
Listing all modifications to your SXResults, the new History panel allows easy tracking of successive data processing steps.



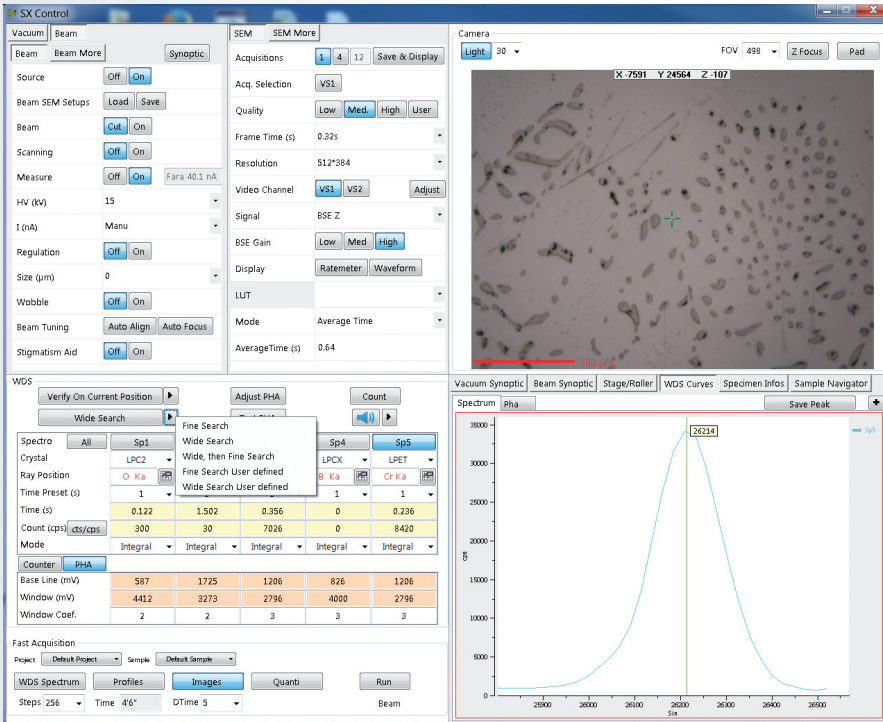
• **New Graphical background modeling capabilities:**

- Provides more data processing flexibility thanks to linear, exponential, power and polynomial fit options
- ensures more accurate background subtraction, useful for the analysis of trace elements.



• **New options for interactive lateral resolution measurement:**

- Provides fast and easy computation of both lateral resolution and interface width, directly from in-line or off-line profiles
- Spatial resolution is computed from signal amplitude between the upper and lower limits: at 16-84%, 20-80%, 30-70% or manually.



• **Improved Peak Search / Peak Area functions:**

- New user-defined Peak Search parameters (scan width, acquisition time and number of channels) ensure a **more accurate peak determination**, especially in case of low intensity peaks
- Peak Search and Peak Area spectra are automatically saved and stored in the calibration data file for future visualization and double-check.

Non-contractual document. CAMECA reserves the right to alter the specifications of its products without notice.